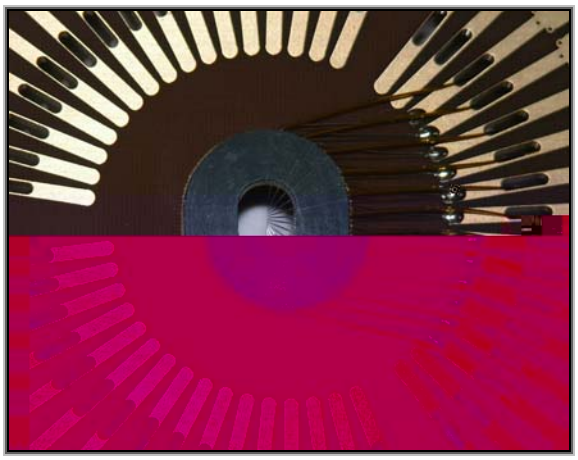
P-Probe™ - Low Leakage 'Parametric' Probe Card Product Specification

ProbeLogic utilizes the latest State-of-the-Art Technology and Equipment to engineer, design, and manufacture high quality and "100% Tested" probe cards. ProbeLogic has the shortest turn-times and the most cost effective test solutions in the industry.



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Devices

Any Type	Parametric or E-Test Applications
Pad Configuration	Single In-line (up to 48)
Pad Pitch/Size	Pad Pitch: ≥ 60u Pad Width: ≥ 50u Length: ≥ 50u
Pad Material	Aluminum, Gold, Copper (or Industry Standard)
Leakage	Guarded Probe - >1pA/V @ 25C

Ring Assembly

Probe Ring	Custom Ceramic
Probe Material	Tungsten, Rhenium Tungsten, Beryllium-Copper, Paliney
Testing Temperature	25°C to 120°C
Probe Diameter	3.0 mils to 10 mils
Tip Diameter	0.5 mils to 5 mils
Tip Shape	Flat or Radius
Tip Length	7 mils (or Build to Customer Spec.)
Contact Resistance	<2.0 ohms
Alignment	+/- 0.20 mils
Planarity	+/- 0.20 mils
Contact Force	0.8 – 3.0 G/mils O.D.
Probe Depth	100 mils to 400 mils (Measured from bottom of PCB)

PCB/Components

PCB Material	Polyimide
PCB Design	Standard 'Generic' or Custom
ATE Type	Parametric – Keithley, Verigy